

Characterisation with test beams of ITk pixel detectors for the upgrade of the ATLAS Inner Detector

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The ATLAS Inner Detector will be replaced with an all-silicon tracking detector (ITk) to cope with the new challenging conditions arising with the High-Luminosity Large Hadron Collider (HL-LHC), where the instantaneous luminosity will increase by three times compared to that of the LHC, and bring higher radiation damage. The pixel detector will be the innermost part of the ITk, consisting of five radial layers. The sensors in different positions are designed with different geometries and technologies, and are procured from different vendors. n^+ -in- p planar hybrid modules with 150 µm and 100 µm thickness will instrument the outer layers, and 3D sensor technology was chosen to instrument the innermost layers due to its radiation hardness. Additionally, the production of the sensors is distributed among four different vendors: HPK, Micron, FBK and SINTEF, with HPK producing the majority of the sensors. As soon as pre-production modules and sensors of different types and produced by different vendors become available, they are being tested with test beams before and after irradiation to assess their performance at the fluence expected at the end of their life during HL-LHC. An overview of the current test beam results is given. The results shown are for pre-production modules equipped with ITkPixV1.1 (RD53B) readout chips. The reconstruction and analysis was done with the Corryvreckan software.

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1. Introduction

The layout of the ATLAS ITk pixel detector is shown in fig. [1,](#page-1-0) and table [1](#page-1-1) summarises the main features of different types of sensors in the detector.

Figure 1: Different regions of the ATLAS ITk Pixel detector [\[1\]](#page-2-0).

Table 1: Technology, geometry, planned positions, vendor, and bias structure of ITk pixel detector sensors.

2. Setup and Data Analysis

Test beam campaigns were conducted in CERN SPS with 120 GeV pion beam and PS with 12 GeV proton beam. Fig. [2](#page-1-2) shows the setup, which includes the EUDET-type beam telescope [\[2\]](#page-2-1) ACONITE, and an FEI4 module as reference. Specifications on the hit detection efficiency ϵ are shown in table [2.](#page-1-3)

Figure 2: Test beam setup.

3. Results HPK Planar: fig. [3](#page-1-4) shows results for an unirradiated and an irradiated module (note

the different threshold). **Figure 3:** Average efficiency before (left) and after (middle) irradiation and Specifications on hit de- in-pixel efficiency (right) for HPK sensors [\[3\]](#page-2-2) measured perpendicular to beam. tection efficiency ϵ are met before and after irradiation, no low efficiency region from bias structures.

SINTEF 3D 50×50 nm^2 pixel pitch: tested before and after irradiation and with different angles of incidence are shown in fig. [4.](#page-1-5) ϵ is within specification. When measured perpendicular to beam direction, the in-pixel effi-

Figure 4: ϵ at different angle and fluence (left), and in-pixel efficiency (middle and right) for normal beam incidence for SINTEF 3D sensors [\[4\]](#page-2-3).

ciency decreased at p^+ columns before irradiation. After irradiation, the efficiency also decreased at n^{+} columns, but this can be due to the relatively low bias voltage.

FBK 3D 50 \times 50 μ m² or 25 \times 100 μ m² pixel pitch: as shown in fig. [5,](#page-2-4) unirradiated 50 \times 50 μ m² sensors were measured in different beam type and energy at 0° beam incidence. After irradiation, ϵ for both sensor pitches meet specification. A fluence beyond requirement (fig. [5d\)](#page-2-4) led to a high number of masked pixels. The in-pixel efficiency decreased at p^+ columns at 0 \degree beam incidence both before and after irradiation, but this effect disappears with tilted beam incidence as expected. Higher irradiation resulted in an efficiency decrease also at n^+ columns, attributed to too low a bias voltage.

(e) 0 Φ, SCC4, 10 V, 0 ° [\[5\]](#page-2-5) **(f)** 1 Φ, SCC5, 100 V, 0 ° [5] **(g)** 1 Φ, SCC5, 90 V, 15 ° [5] **(h)** $\leq 1.5 \Phi$, SCC3, 100 V, 0 \degree [\[6\]](#page-2-6) **Figure 5:** ϵ and in-pixel efficiency for FBK 3D sensors measured at different fluence and angle. Φ = 10^{16} n_{eq}/cm². The highest irradiation fluence in fig. [5d](#page-2-4) is beyond requirement.

4. Conclusions & Outlook

The hit detection efficiency of HPK, FBK and SINTEF sensors meet specification at required bias voltage both before irradiation and after irradiated to around the expected fluence. In-pixel efficiency for HPK planar sensors and at tilted position for 3D sensors showed no decrease due to bias structures, and decreased for 3D sensors at etched columns when measured perpendicular to beam. Measurements of production modules with the final read-out chip version ITkPixV2 [\[8\]](#page-2-8) using EUDAQ2 [\[9\]](#page-2-9) as well as Corryvreckan [\[10\]](#page-2-10) versions that include new developments are ongoing.

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